



Microelectronics Failure Analysis DVD Lecture Series

Presented by:
University of New Mexico
&
Soft Test Inc.

Soft Test has partnered with the University of New Mexico to offer a comprehensive lecture series that covers a wide range of topics associated with semiconductors and failure analysis. The University of New Mexico invited eighteen experts to give a total of 30 lectures associated with Failure Analysis. The goal was to fill a gap in instruction at the university level and expose students to the thoughts from leading practitioners in the field. These lectures provide a wealth of practical information and insight into current FA issues.

Each guest lecturer is currently practicing Failure Analysis in industry and offers a unique view based upon their actual experience. The series addresses several major subject areas: Electron, Optical, SQUID & Atomic Force Microscopy, MEMS Failure Analysis, Integrated Circuit Debug and Validation, and Advanced Fault Isolation Techniques.

Each of the 30 lectures is approximately 75 minutes long, total lecture time is approximately 37.5 hours. All lectures are available in their entirety on DVD.

The lectures were presented at the UNM and the audience consisted of local UNM students, engineers from the area (Intel, Sandia Labs, Los Alamos Labs), and a nation wide audience from the National Technology University (NTU).

You can purchase the entire Lecture Series Set (30) lectures for **\$3,995** or they are offered in sets of 3 lectures per DVD, priced at **\$500 per DVD**. Discounts are offered for purchases of 3 or more individual DVDs.

The Power Point notes used in the lectures are included with your purchase. Visit our web site to view video samples of each lecture.



Microelectronics Failure Analysis DVD Lecture Series

DVD	Lecture	Topics	Presenter
DVD # 1	1	Introduction to Failure Analysis	Rich Anderson - Sandia Labs
	2	Basic Failure Analysis Techniques I	Chris Henderson - Semitracks Inc.
	3	Basic Failure Analysis Techniques II	Chris Henderson - Semitracks Inc.
DVD # 2	4	Electron Microscopy	Larry Wagner - Texas Instruments
	5	Fault Isolation Scanning Optical Microscopy	Ed Cole - Sandia Labs
	6	IC Packaging Technology & Analytical Methods	Tom Moore - Omniprobe, Inc.
DVD # 3	7	Decapsulation and Package Analysis	Mike Strizich - ASI
	8	Fault Isolation Optical Techniques	Ed Cole - Sandia Labs
	9	Atomic Force Microscopy	Pai Tangyunyong - Sandia Labs
DVD # 4	10	Deprocessing and Sample Preparation	Mike Strizich - ASI
	11	Soft Defect Localization	Ed Cole - Sandia Labs
	12	Advanced Fault Isolation - Thermal Imaging	Dan Barton - Sandia Labs
DVD # 5	13	Issues of Backside Sample Prep	Dan Barton - Sandia Labs
	14	Backside Analysis Techniques	Mike Bruce - AMD
	15	Photoemission Techniques	Dan Barton - Sandia Labs
DVD # 6	16	Electronics of Failure I	Chuck Hawkins - UNM
	17	Electronics of Failure II	Chuck Hawkins - UNM
	18	Optoelectronic Device FA	Dan Barton - Sandia Labs



Microelectronics Failure Analysis DVD Lecture Series

DVD # 7	19	EOS / ESD	Chuck Hawkins - UNM
	20	Advanced Fault Isolation 1: SQUID microscopy	Lee Knaus - Neocera Corp.
	21	Advanced Fault Isolation 2: SQUID microscopy	Lee Knaus - Neocera Corp.
DVD # 8	22	Focused Ion Beam (FIB) methods	Joe Michael Sandia Labs
	23	MEMS Failure Analysis I	Jerry Walraven - Sandia Labs
	24	MEMS Failure Analysis 2	Jerry Walraven - Sandia Labs
DVD # 9	25	Failure Analysis in High Volume Manufacturing	Kathy Clark
	26	Integrated Circuit Debug and Validation	Lawrence Clark - UNM
	27	Elemental Analysis for FA	Paul Kotula - Sandia Labs
DVD # 10	28	Focus on Structural Test: AC Scan	Alfred Crouch Inovys Corp.
	29	Failure Analysis Lab Management	Dick Ross - IBM
	30	Course Summary	Chuck Hawkins - UNM

Ordering Information:

The entire Lecture Series Set (30) lectures can be purchased for **\$3,995** or lectures are offered in sets of 3 per DVD as shown above, priced at **\$500 per DVD**. Visit our web site to view video samples of each lecture.

The Power Point notes used in the lectures are included with your purchase.

Order on-line at www.soft-test.com